

# Lu Liu

## List of Publications by Year in descending order

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47  
papers

1,199  
citations

430442

18  
h-index

377514

34  
g-index

49  
all docs

49  
docs citations

49  
times ranked

1174  
citing authors

#	ARTICLE	IF	CITATIONS
1	Radiation effects in GaN materials and devices. Journal of Materials Chemistry C, 2013, 1, 877-887.	2.7	171
2	Review of radiation damage in GaN-based materials and devices. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2013, 31, .	0.9	170
3	Inkjet Printing Transparent and Conductive MXene ( $\text{Ti}_3\text{C}_2\text{T}_x$ ) Films: A Strategy for Flexible Energy Storage Devices. ACS Applied Materials & Interfaces, 2021, 13, 17766-17780.	4.0	79
4	Functionalization with MXene ( $\text{Ti}_3\text{C}_2$ ) Enhances the Wettability and Shear Strength of Carbon Fiber-Epoxy Composites. ACS Applied Nano Materials, 2019, 2, 5553-5562.	2.4	60
5	Isolation blocking voltage of nitrogen ion-implanted AlGaIn/GaN high electron mobility transistor structure. Applied Physics Letters, 2010, 97, .	1.5	49
6	Three-Dimensional Porous $\text{Ti}_3\text{C}_2\text{Tx-NiO}$ Composite Electrodes with Enhanced Electrochemical Performance for Supercapacitors. Materials, 2019, 12, 188.	1.3	44
7	Construction of biomimetic artificial intervertebral disc scaffold via 3D printing and electrospinning. Materials Science and Engineering C, 2021, 128, 112310.	3.8	38
8	Characterization of the gate oxide of an AlGaIn/GaN high electron mobility transistor. Applied Physics Letters, 2011, 98, 122103.	1.5	34
9	Modeling Proton Irradiation in AlGaIn/GaN HEMTs: Understanding the Increase of Critical Voltage. IEEE Transactions on Nuclear Science, 2013, 60, 4103-4108.	1.2	34
10	Dependence on proton energy of degradation of AlGaIn/GaN high electron mobility transistors. Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics, 2013, 31, .	0.6	34
11	Degradation Mechanisms for GaN and GaAs High Speed Transistors. Materials, 2012, 5, 2498-2520.	1.3	32
12	Investigation of the effect of temperature during off-state degradation of AlGaIn/GaN High Electron Mobility Transistors. Microelectronics Reliability, 2012, 52, 23-28.	0.9	32
13	Comparison of neutron irradiation effects in AlGaIn/AlN/GaN, AlGaIn/GaN, and InAlN/GaN heterojunctions. Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics, 2012, 30, .	0.6	29
14	Effects of proton irradiation energies on degradation of AlGaIn/GaN high electron mobility transistors. Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics, 2012, 30, 012202.	0.6	26
15	Effect of source field plate on the characteristics of off-state, step-stressed AlGaIn/GaN high electron mobility transistors. Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics, 2011, 29, .	0.6	25
16	Impact of proton irradiation on dc performance of AlGaIn/GaN high electron mobility transistors. Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics, 2013, 31, 042202.	0.6	23
17	Effect of electron irradiation on AlGaIn/GaN and InAlN/GaN heterojunctions. Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics, 2013, 31, 022206.	0.6	23
18	Improvement of Off-State Stress Critical Voltage by Using Pt-Gated AlGaIn/GaN High Electron Mobility Transistors. Electrochemical and Solid-State Letters, 2011, 14, H264.	2.2	21

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19	Effect of temperature on CO sensing response in air ambient by using ZnO nanorod-gated AlGaIn/GaN high electron mobility transistors. <i>Sensors and Actuators B: Chemical</i> , 2013, 176, 708-712.	4.0	19
20	Effects of proton irradiation on dc characteristics of InAlN/GaN high electron mobility transistors. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2011, 29, 061201.	0.6	17
21	Annealing temperature dependence of Ohmic contact resistance and morphology on InAlN/GaN high electron mobility transistor structures. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2011, 29, 021002.	0.6	16
22	Effect of buffer structures on AlGaIn/GaN high electron mobility transistor reliability. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2013, 31, 011805.	0.6	16
23	Study on the effects of proton irradiation on the dc characteristics of AlGaIn/GaN high electron mobility transistors with source field plate. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2014, 32, 022202.	0.6	16
24	Transmission electron microscopy characterization of electrically stressed AlGaIn/GaN high electron mobility transistor devices. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2012, 30, .	0.6	14
25	Effect of buffer layer structure on electrical and structural properties of AlGaIn/GaN high electron mobility transistors. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2012, 30, 011205.	0.6	13
26	MXene (Ti <sub>3</sub> C <sub>2</sub> T <sub>x</sub> ) Functionalized Short Carbon Fibers as a Cross-Scale Mechanical Reinforcement for Epoxy Composites. <i>Polymers</i> , 2021, 13, 1825.	2.0	13
27	Investigating the effect of off-state stress on trap densities in AlGaIn/GaN high electron mobility transistors. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2011, 29, .	0.6	12
28	Comparison of passivation layers for AlGaIn/GaN high electron mobility transistors. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2011, 29, .	0.6	12
29	Under-gate defect formation in Ni-gate AlGaIn/GaN high electron mobility transistors. <i>Microelectronics Reliability</i> , 2012, 52, 2542-2546.	0.9	12
30	Electrical characterization of 60Co gamma radiation-exposed InAlN/GaN high electron mobility transistors. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2013, 31, .	0.6	11
31	Circular and rectangular via holes formed in SiC via using ArF based UV excimer laser. <i>Applied Surface Science</i> , 2011, 257, 2303-2307.	3.1	9
32	Effects of silicon nitride passivation on isolation-blocking voltage in AlGaIn/GaN high electron mobility transistors. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2011, 29, .	0.6	9
33	Proton irradiation energy dependence of dc and rf characteristics on InAlN/GaN high electron mobility transistors. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2012, 30, 041206.	0.6	9
34	PVdF-HFP-Based Gel Polymer Electrolyte with Semi-Interpenetrating Networks For Dendrite-Free Lithium Metal Battery. <i>Acta Metallurgica Sinica (English Letters)</i> , 2021, 34, 417-424.	1.5	9
35	Attapulgate@MXene Hybrids with Ti <sub>3</sub> C <sub>2</sub> T <sub>x</sub> Lamellae Surface Modified by Attapulgate as a Mechanical Reinforcement for Epoxy Composites. <i>Polymers</i> , 2021, 13, 1820.	2.0	9
36	Effects of 2 MeV Ge <sup>+</sup> irradiation on AlGaIn/GaN high electron mobility transistors. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2013, 31, 021205.	0.6	8

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37	Carbon monoxide detection sensitivity of ZnO nanorod-gated AlGaIn/GaN high electron mobility transistors in different temperature environments. <i>Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics</i> , 2012, 30, 010606.	0.6	7
38	Methane detection using Pt-gated AlGaIn/GaN high electron mobility transistor based Schottky diodes. <i>Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics</i> , 2013, 31, 032203.	0.6	7
39	Thermal simulation of laser lift-off AlGaIn/GaN high electron mobility transistors mounted on AlN substrates. <i>Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics</i> , 2011, 29, 041202.	0.6	6
40	Effect of Drain Bias on Degradation of AlGaIn/GaN High Electron Mobility Transistors under X-Band Operation. <i>Electrochemical and Solid-State Letters</i> , 2011, 14, H464.	2.2	5
41	Degradation of dc characteristics of InAlN/GaN high electron mobility transistors by 5 MeV proton irradiation. <i>Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics</i> , 2012, 30, 031202.	0.6	5
42	193-nm excimer laser lift-off for AlGaIn/GaN high electron mobility transistors. <i>Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics</i> , 2012, 30, 051209.	0.6	5
43	Mechanical properties of phase-pure bulk Ta <sub>4</sub> AlC <sub>3</sub> prepared by spark plasma sintering and subsequent heat treatment. <i>Processing and Application of Ceramics</i> , 2021, 15, 211-218.	0.4	5
44	Comparison of DC performance of Pt/Ti/Au- and Ni/Au-gated AlGaIn/GaN high electron mobility transistors. <i>Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics</i> , 2011, 29, 042202.	0.6	3
45	Radiation Damage in GaN-Based Materials and Devices. , 2013, , 1753-1764.		2
46	The Effects of Device Dimension, Substrate Temperature, and Gate Metallization on the Reliability of AlGaIn/GaN High Electron Mobility Transistors. <i>Materials Research Society Symposia Proceedings</i> , 2012, 1396, .	0.1	0
47	Flexible and High-Performance MXene/MnO <sub>2</sub> Film Electrodes Fabricated by Inkjet Printing: Toward a New Generation Supercapacitive Application ( <i>Adv. Mater. Interfaces</i> 21/2021). <i>Advanced Materials Interfaces</i> , 2021, 8, 2170117.	1.9	0